



**FLASH-ROM MODULE 32MByte (8M x 32Bit), 72-Pin SIMM, 5V**  
**Part No. HMF8M32M8A**

## GENERAL DESCRIPTION

The HMF8M32M8A is a high-speed flash read only memory (FROM) module containing 16,777,216 words organized in a x32bit configuration. The module consists of eight 4M x 8bit FROM mounted on a 72-pin, double-sided, FR4-printed circuit board. Commands are written to the command register using standard microprocessor write timings.

Register contents serve as input to an internal state-machine, which controls the erase and programming circuitry. Write cycles also internally latch addresses and data needed for the programming and erase operations. Reading data out of the device is similar to reading from 12.0V flash or EPROM devices.

Eight chip enable inputs, (/CE\_UU1, /CE\_UM1, /CE\_LM1, /CE\_LL1, /CE\_UU2, /CE\_UM2, /CE\_LM2, CE\_LL2) are used to enable the module's 4 bytes independently. Outputs enable (/OE) and write enable (/WE) can set the memory input and output. When FROM module is disable condition the module is becoming power standby mode, system designer can get low-power design. All module components may be powered from a single +5V DC power supply and all inputs and outputs are TTL-compatible.

## FEATURES

### w Part Identifications

HMF8M32M8A : 32Mbyte, 72-pin SIMM, Gold

w Access time : 55, 70, 90

w High-density 32MByte design

w High-reliability, low-power design

w Single + 5V  $\pm$  0.5V power supply

w Easy memory expansion

w All inputs and outputs are TTL-compatible

w FR4-PCB design

w Low profile 72-pin SIMM

w Minimum 100,000 write/erase cycle

w Sectors erase architecture

w Sector group protection

w Temporary sector group unprotection

w The used device is Am29F032B or M29F032D

## OPTIONS

### w Timing

55ns access -55

70ns access -70

90ns access -90

### w Packages

72-pin SIMM M

## MARKING

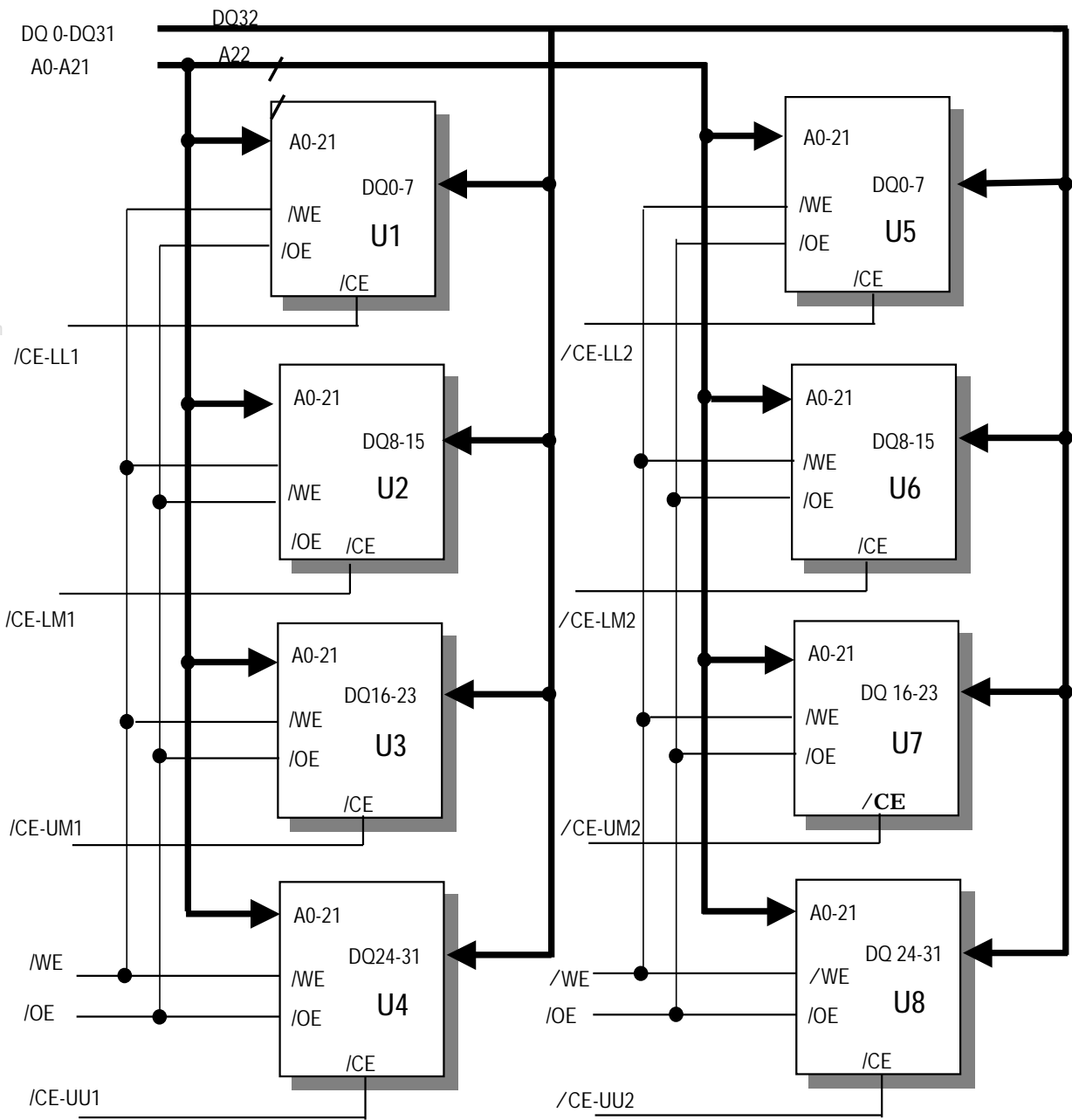
## PIN ASSIGNMENT

PIN	SYMBOL	PIN	SYMBOL	PIN	SYMBOL
1	Vss	25	A20	49	DQ17
2	A3	26	DQ8	50	DQ18
3	A2	27	DQ9	51	DQ22
4	A1	28	DQ10	52	DQ21
5	A0	29	/CE-LM2	53	DQ20
6	Vcc	30	Vcc	54	DQ19
7	A11	31	/CE-LM1	55	A19
8	/OE	32	DQ15	56	A15
9	A10	33	DQ14	57	A12
10	/RESET	34	DQ13	58	A7
11	/CE-LL2	35	DQ12	59	Vcc
12	/CE-LL1	36	DQ11	60	A8
13	DQ7	37	A18	61	A9
14	DQ0	38	A16	62	DQ24
15	DQ1	39	Vss	63	DQ25
16	DQ2	40	A6	64	DQ26
17	DQ6	41	A21	65	/CE-UU2
18	DQ5	42	A5	66	/CE-UU1
19	DQ4	43	A4	67	DQ31
20	DQ3	44	Vcc	68	DQ30
21	/WE	45	/CE-UM2	69	DQ29
22	A17	46	/CE-UM1	70	DQ28
23	A14	47	DQ23	71	DQ27
24	A13	48	DQ16	72	Vss

72-PIN SIMM

TOP VIEW

FUNCTIONAL BLOCK DIAGRAM



## TRUTH TABLE

MODE	/OE	/CE	/WE	DQ	POWER
STANDBY	X	H	X	HIGH-Z	STANDBY
NOT SELECTED	H	L	H	HIGH-Z	ACTIVE
READ	L	L	H	Q	ACTIVE
WRITE or ERASE	X	L	L	D	ACTIVE

**NOTE:** X means don't care

## ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	RATING
Voltage with respect to ground all other pins	$V_{IN,OUT}$	-0.6V to + $V_{CC}$ +0.6V
Voltage with respect to ground $V_{CC}$	$V_{CC}$	-0.60V to + 6.0V
Storage Temperature	$T_{STG}$	-65°C to + 125°C
Operating Temperature	$T_A$	-40°C to + 85°C

<sup>w</sup> Stresses greater than those listed under " Absolute Maximum Ratings" may cause permanent damage to the device.

This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operating section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

## RECOMMENDED DC OPERATING CONDITIONS

PARAMETER	SYMBOL	MIN	TYP.	MAX
$V_{CC}$ for $\pm 10\%$ device Supply Voltages	$V_{CC}$	4.5V		5.5V
Ground	$V_{SS}$	0	0	0

DC AND OPERATING CHARACTERISTICS ( $0^{\circ}\text{C} \leq T_A \leq 70^{\circ}\text{C}$ ;  $V_{CC} = 5\text{V} \pm 0.5\text{V}$ )

PARAMETER	TEST CONDITIONS	SYMBOL	MIN	MAX	UNITS
Input Leakage Current	$V_{CC}=V_{CC}$ max, $V_{IN}=\text{GND to } V_{CC}$	$I_{L1}$		$\pm 1.0$	$\mu\text{A}$
Output Leakage Current	$V_{CC}=V_{CC}$ max, $V_{OUT}=\text{GND to } V_{CC}$	$I_{L0}$		$\pm 1.0$	$\mu\text{A}$
Output High Voltage	$I_{OH} = -2.5\text{mA}$ , $V_{CC} = V_{CC}$ min	$V_{OH}$	2.4		V
Output Low Voltage	$I_{OL} = 12\text{mA}$ , $V_{CC} = V_{CC}$ min	$V_{OL}$		0.45	V
$V_{CC}$ Active Current for Read(1)	$/CE = V_{IL}$ , $/OE=V_{IH}$	$I_{CC1}$		40	mA
$V_{CC}$ Active Current for Program or Erase(2)	$/CE = V_{IL}$ , $/OE=V_{IH}$	$I_{CC2}$		60	mA
$V_{CC}$ Standby Current	$/CE= V_{IH}$	$I_{CC3}$		1.0	mA
Low $V_{CC}$ Lock-Out Voltage		$V_{LKO}$	3.2	4.2	V

## Notes:

1. The  $I_{CC}$  current listed is typically less than 2mA/MHz, with  $/OE$  at  $V_{IH}$ .
2.  $I_{CC}$  active while embedded algorithm (program or erase) is in progress
3. Maximum  $I_{CC}$  current specifications are tested with  $V_{CC}=V_{CC}$  max

**ERASE AND PROGRAMMING PERFORMANCE**

PARAMETER	LIMITS			UNIT	COMMENTS
	MIN.	TYP.	MAX.		
Sector Erase Time	-	1	8	sec	Excludes 00H programming prior to erasure
Chip Erase Time	-	64		sec	
Byte Programming Time	-	7	300	μs	Excludes system-level overhead
Chip Programming Time	-	28.8	86.4	sec	

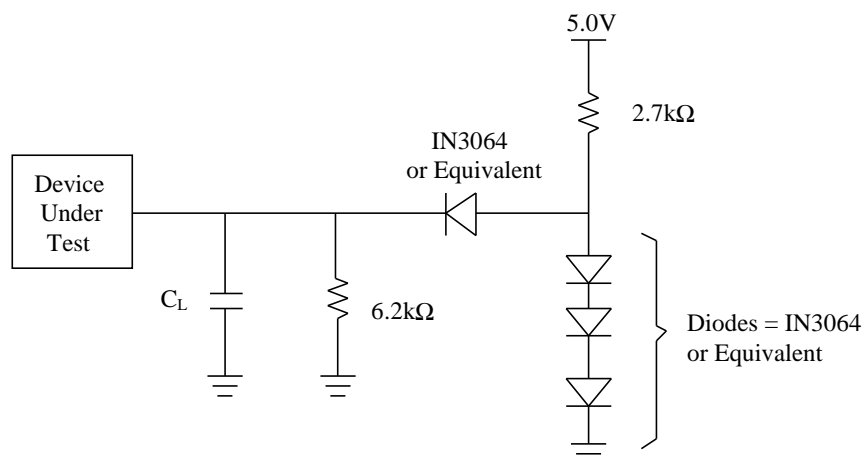
**TSOP CAPACITANCE**

PARAMETER SYMBOL	PARAMETER DESCRIPTION	TEST SETUP	MIN	MAX	UNIT
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 0	6	7.5	pF
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 0	8.5	12	pF
C <sub>IN2</sub>	Control Pin Capacitance	V <sub>IN</sub> = 0	7.5	9	pF

Notes : Test conditions T<sub>A</sub> = 25° C, f=1.0 MHz.

**TEST SPECIFICATIONS**

TEST CONDITION	ALL SPEED OPTIONS	UNIT
Output load	1TTL gate	
Output load capacitance, C <sub>L</sub> (Including jig capacitance)	100	pF
Input rise and full times	20	ns
Input pulse levels	0.45-2.4	V
Input timing measurement reference levels	0.8	V
Output timing measurement reference levels	2.0	V

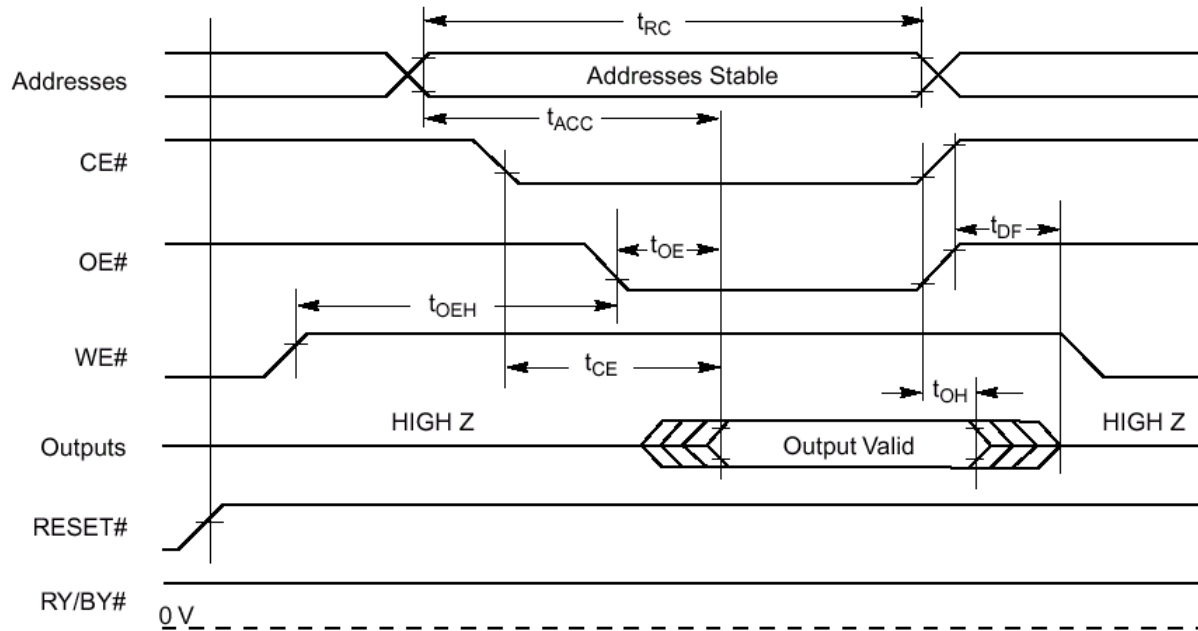


Note : C<sub>L</sub> = 100pF including jig capacitance

AC CHARACTERISTICS

Read Only Operations Characteristics

PARAMETER SYMBOLS		DESCRIPTION	TEST SETUP		SPEED OPTIONS			UNIT
JEDEC	STANDARD				-55	-70	-90	
$t_{AVAV}$	$t_{RC}$	Read Cycle Time		Min	55	70	90	ns
$t_{AVQV}$	$t_{ACC}$	Address to Output Delay	$/CE = V_{IL}$ $/OE = V_{IL}$	Max	55	70	90	ns
$t_{ELQV}$	$t_{CE}$	Chip Enable to Output Delay	$/OE = V_{IL}$	Max	55	70	90	ns
$t_{GLQV}$	$t_{OE}$	Chip Enable to Output Delay		Max	30	40	40	ns
$t_{EHQZ}$	$t_{DF}$	Chip Enable to Output High-Z		Max	18	20	20	ns
$t_{GHQZ}$	$t_{DF}$	Output Enable to Output High-Z		Max	18	20	20	ns
$t_{AXQX}$	$t_{QH}$	Output Hold Time From Addresses, $/CE$ or $/OE$ , Whichever Occurs First		Min	0	0	0	ns

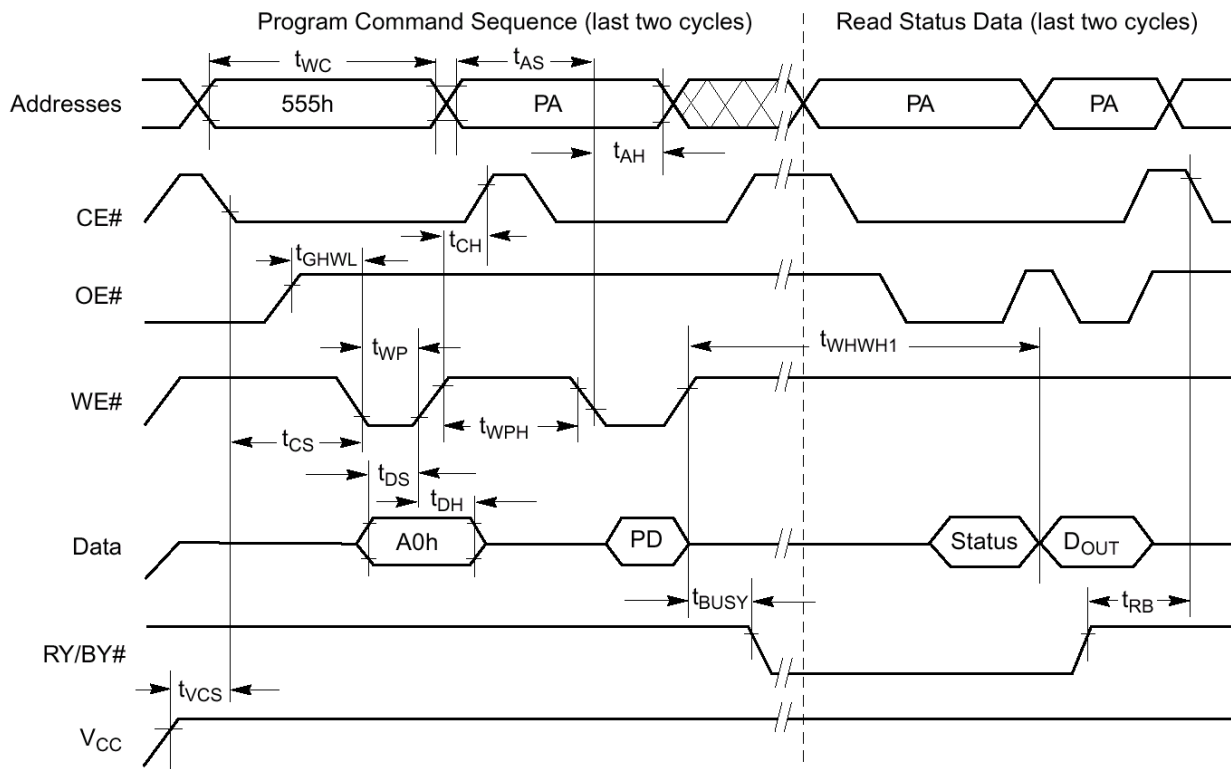


u Erase/Program Operations

PARAMETER SYMBOLS		DESCRIPTION		-55	-70	-90	UNIT
JEDEC	STANDARD						
$t_{AVAV}$	$t_{WC}$	Write Cycle Time	Min	55	70	90	ns
$t_{AVWL}$	$t_{AS}$	Address Setup Time	Min	0	0	0	ns
$t_{WLAX}$	$t_{AH}$	Address Hold Time	Min	45	45	45	ns
$t_{DVWH}$	$t_{DS}$	Data Setup Time	Min	45	45	45	ns
$t_{WHDX}$	$t_{DH}$	Data Hold Time	Min	0	0	0	ns
$t_{GHWL}$	$t_{GHWL}$	Read Recover Time Before Write	Min	0	0	0	ns
$t_{ELWL}$	$t_{CS}$	/CE Setup Time	Min	0	0	0	ns
$t_{WHEH}$	$t_{CH}$	/CE Hold Time	Min	0	0	0	ns
$t_{WLWH}$	$t_{WP}$	Write Pulse Width	Min	45	45	45	ns
$t_{WHWL}$	$t_{WPH}$	Write Pulse Width High	Min	20	20	20	ns
	$t_{VCS}$	Vcc set up time	Min	50	50	50	$\mu$ s

Notes :

1. This does not include the preprogramming time
2. This timing is only for Sector Protect operations



## u Erase/Program Operations

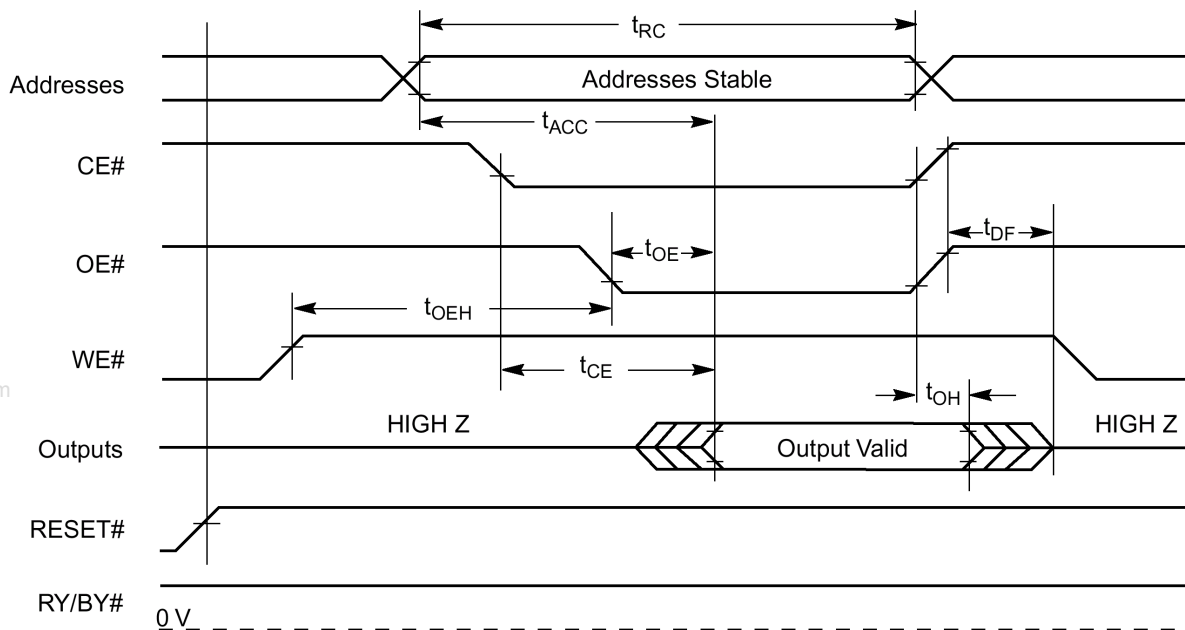
### Alternate /CE Controlled Writes

PARAMETER SYMBOLS		DESCRIPTION		-55	-70	-90	UNIT
JEDEC	STANDARD						
t <sub>AVAV</sub>	t <sub>WC</sub>	Write Cycle Time	Min	55	70	90	ns
t <sub>AVWL</sub>	t <sub>AS</sub>	Address Setup Time	Min	0	0	0	ns
t <sub>WLAX</sub>	t <sub>AH</sub>	Address Hold Time	Min	45	45	45	ns
t <sub>DVWH</sub>	t <sub>DS</sub>	Data Setup Time	Min	45	45	45	ns
t <sub>WHDX</sub>	t <sub>DH</sub>	Data Hold Time	Min	0	0	0	ns
t <sub>GHWL</sub>	t <sub>GHWL</sub>	Read Recover Time Before Write	Min	0	0	0	ns
t <sub>ELWL</sub>	t <sub>CS</sub>	/CE Setup Time	Min	0	0	0	ns
t <sub>WHEH</sub>	t <sub>CH</sub>	/CE Hold Time	Min	0	0	0	ns
t <sub>WLWH</sub>	t <sub>WP</sub>	Write Pulse Width	Min	45	45	45	ns
t <sub>WHWL</sub>	t <sub>WPH</sub>	Write Pulse Width High	Min	20	20	20	ns

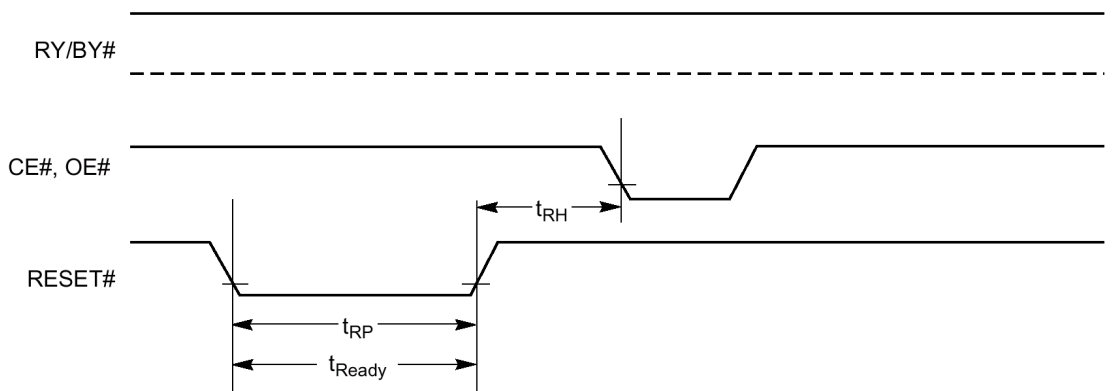
#### Notes :

1. This does not include the preprogramming time
2. This timing is only for Sector Protect operations

u READ OPERATIONS TIMING

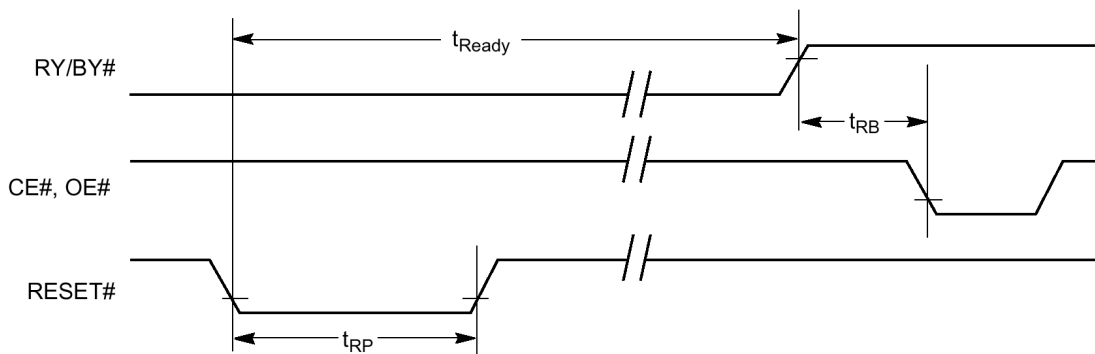


u RESET TIMING



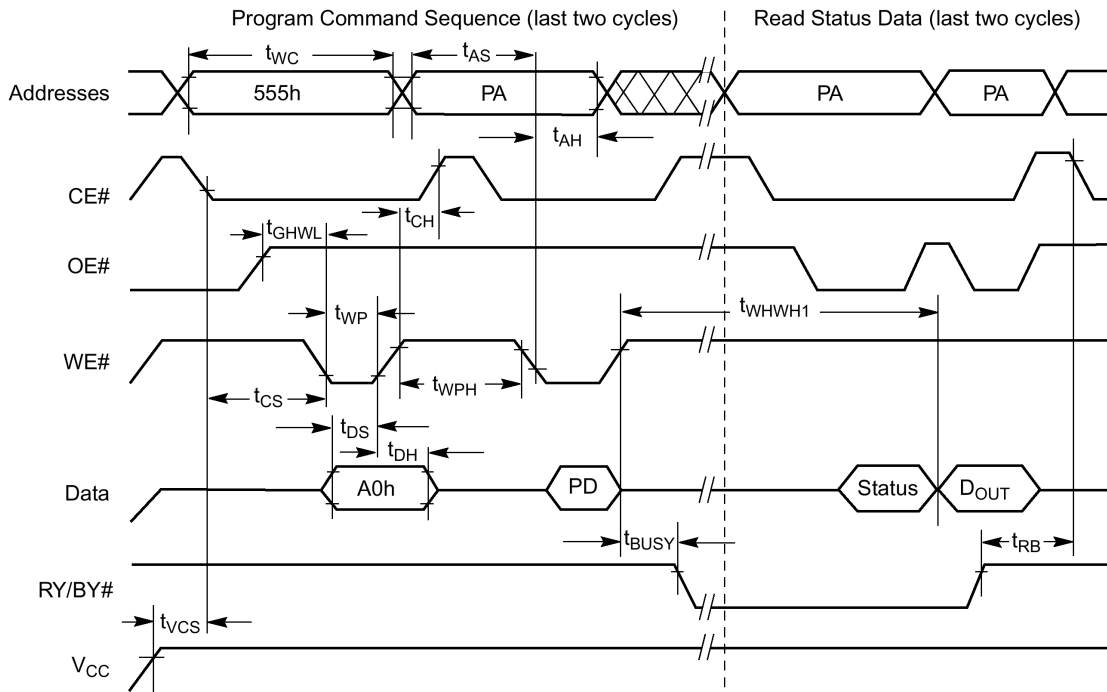
Reset Timings NOT during Embedded Algorithms

Reset Timings during Embedded Algorithms

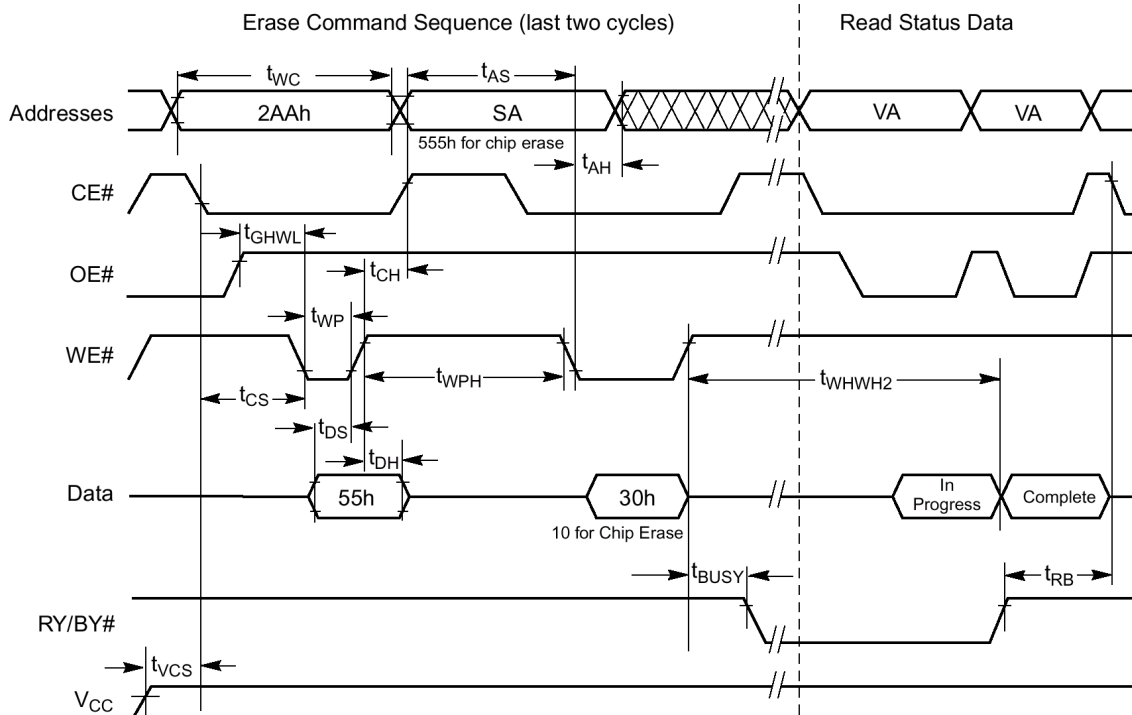




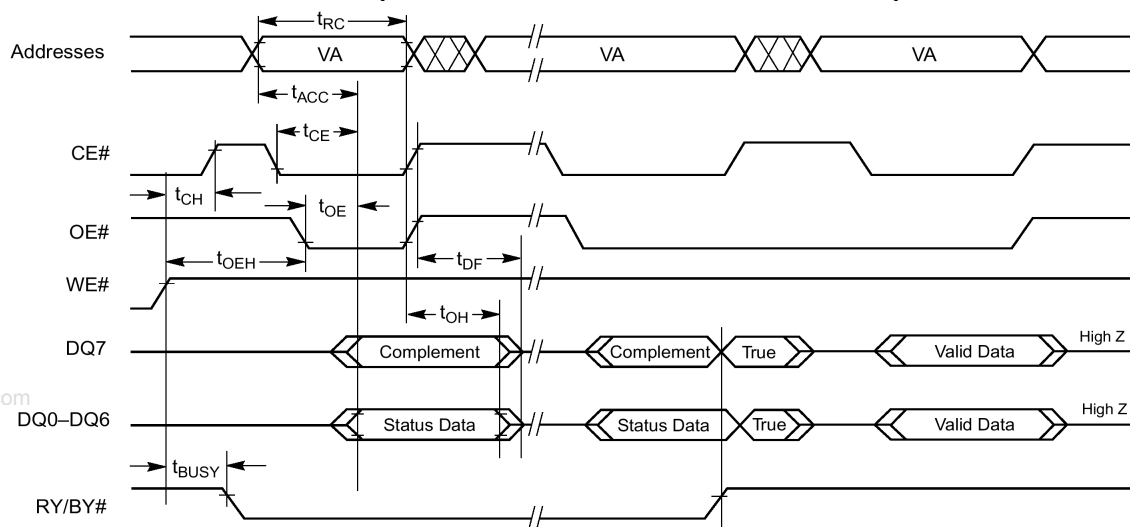
PROGRAM OPERATIONS TIMING



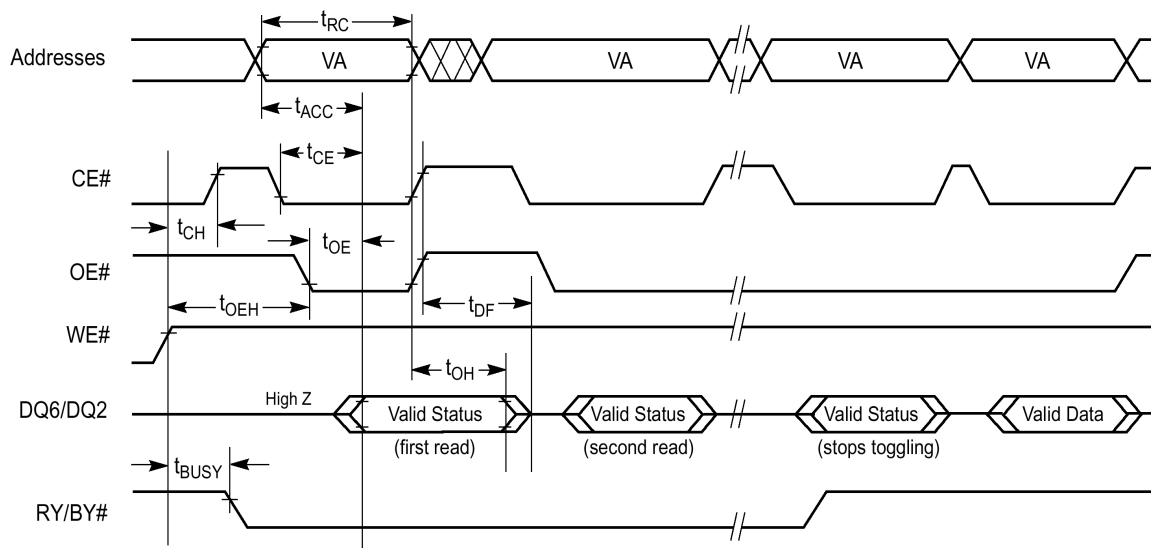
CHIP/SECTOR ERASE OPERATION TIMINGS



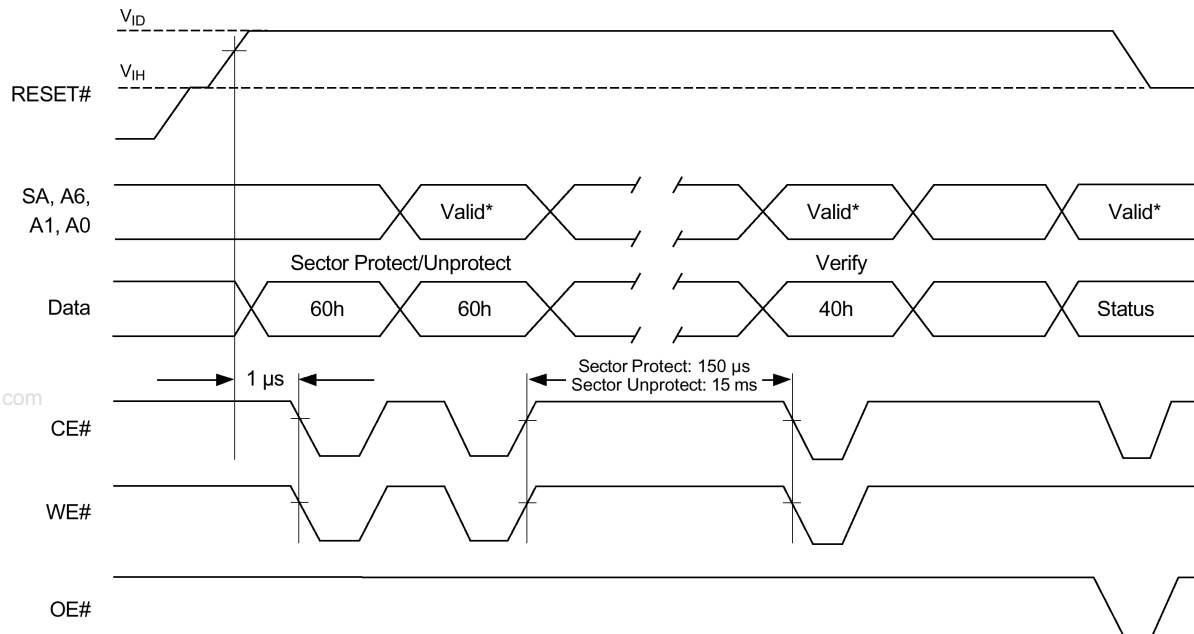
**DATA# POLLING TIMES(DURING EMBEDDED ALGORITHMS)**



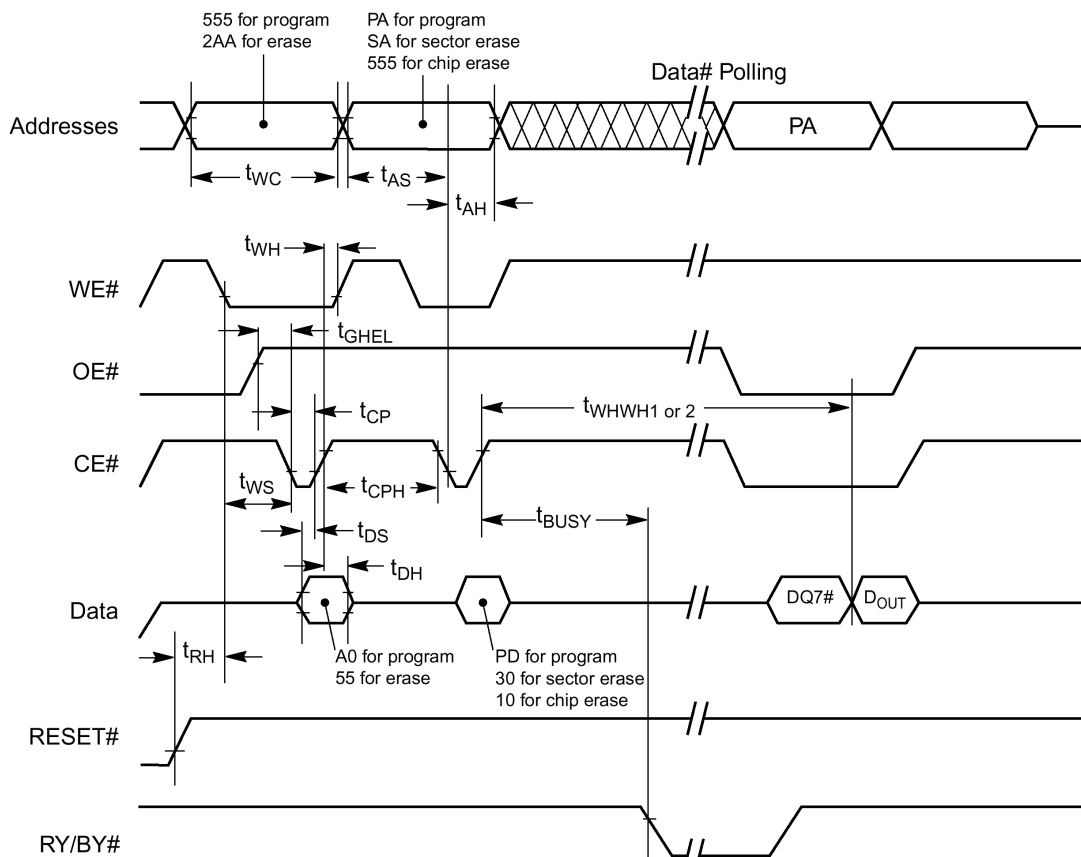
**TOGGLE# BIT TIMINGS (DURING EMBEDDED ALGORITHMS)**



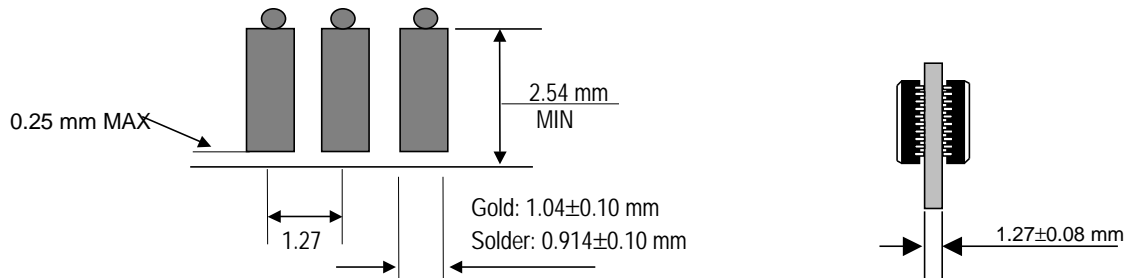
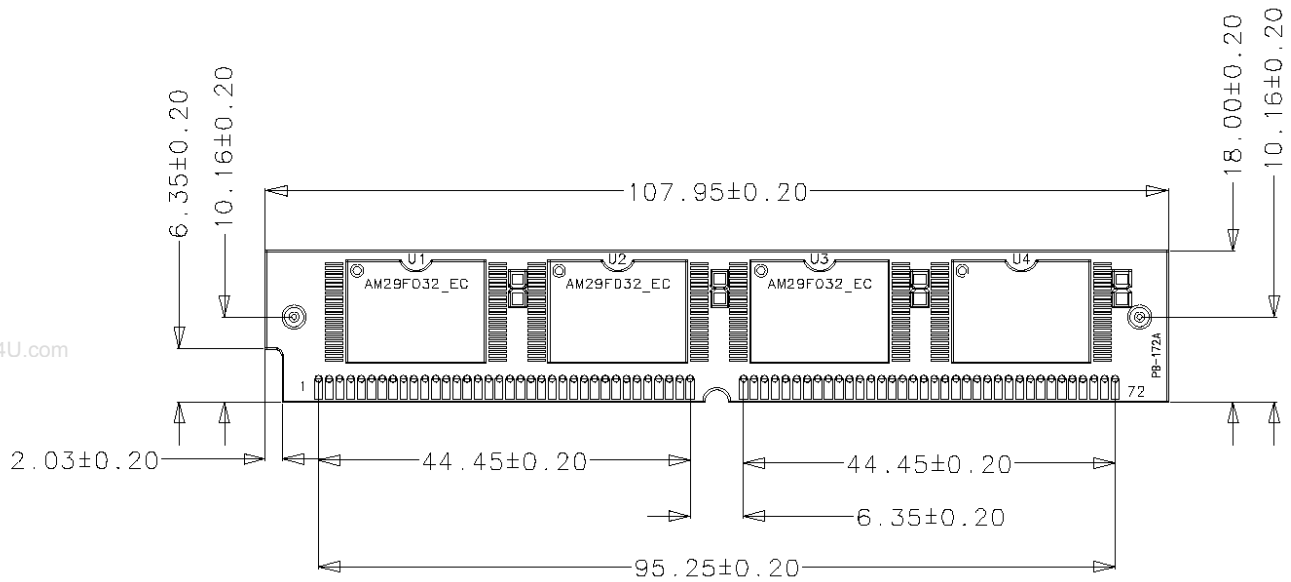
U SECTOR PROTECT UNPROTECT TIMEING DIAGRAM



U ALTERNATE CE# CONTROLLED WRITE OPERATING TIMINGS



PACKAGE DIMENSIONS



(Solder & Gold Plating)

ORDERING INFORMATION

Part Number	Density	Org.	Package	Component Number	Vcc	SPEED
HMF8M32M8A-55	32MByte	8MX 32bit	72 Pin-SIMM	8EA	5V	55ns
HMF8M32M8A-70	32MByte	8MX 32bit	72 Pin-SIMM	8EA	5V	70ns
HMF8M32M8A-90	32MByte	8MX 32bit	72 Pin-SIMM	8EA	5V	90ns